

<b>Notice of References Cited</b>	Application/Control No. 10/694,787		Applicant(s)/Patent Under Reexamination LIN ET AL.	
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*	B	US-6,147,725	11-2000	Yuuki et al.	349/65
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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